

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	:2	("6887722").PN.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB	OR	OFF	2008/06/27 14:38
S1	:2	("4641967").PN.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB	OR	OFF	2008/06/24 16:47
S2	:2	("4881863").PN.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB	OR	OFF	2008/06/24 16:49
S3	:2	("5274434").PN.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB	OR	OFF	2008/06/24 16:51
S4	:2	("6198982").PN.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERVENT; IBM_TDB	OR	OFF	2008/06/24 16:59

S5	1123	((defect\$3 or identif\$7 or determin\$5) with (semiconductor or wafer or IC or circuit or mask)) and (area) and ((first near5 image) same (second near5 image) same (compar\$5 or match\$5) same signal)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/24 17:06
S6	27265	382/144,145,147.ccls. 438/16,401,462,800.ccls. 716/2,19,20,21.ccls. 356/237,4,237,5,394.ccls. 430/4,5,30.ccls. 700/96,97,105,120,121.ccls. 348/86,87,125,126,127,128,129,130,131,132,133,134.ccls.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/24 17:10
S7	89	S5 and S6	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/24 17:10
S8	2	("6947587").PN.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/24 18:02
S9	3795	((defect\$3 or identif\$7 or determin\$5) with (semiconductor or wafer or IC or circuit or mask)) and ((reference or template) with defect\$4 with (device or circuit or wafer or mask or IC))	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/26 16:13
S10	27293	382/144,145,147.ccls. 438/16,401,462,800.ccls. 716/2,19,20,21.ccls. 356/237,4,237,5,394.ccls. 430/4,5,30.ccls. 700/96,97,105,120,121.ccls. 348/86,87,125,126,127,128,129,130,131,132,133,134.ccls.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/26 16:14

S11	670	S9 and S10	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/26 16:14
S12	322	S11 and @ad<"20010517"	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/26 16:19
S13	1	((detected\$3 or identified\$7 or determined\$5) with (semiconductor or wafer or IC or circuit or mask)) and (backside with focus) and (frontside with spin\$1on) and (frontside with lift\$1off)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/26 16:30
S14	144	((detected\$3 or identified\$7 or determined\$5) with (semiconductor or wafer or IC or circuit or mask)) and ((backside with focus) or (frontside with spin\$1on) or (frontside with lift\$1off))	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/26 16:31
S15	14	S10 and S14	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/26 16:32
S16	25	((detected\$3 or identified\$7 or determined\$5) with (semiconductor or wafer or IC or circuit or mask)) and ((backside with focus with (spot or region or area)) or (frontside with resist\$4 with spin\$1on) or (frontside with resist\$4 with lift\$1off))	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/26 16:35

6/27/08 3:36:21 PM

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